

Notice of References Cited

Application/Control No.

10/675,348

Applicant(s)/Patent Under
Reexamination
WATANABE ET AL.

Examiner

JOHN Wahnkyo LEE

Art Unit

2624

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nagasawa et al., "Application of Fourier Transform Infrared Emission Spectrometry to Surface Analysis," March/April 1984, Vol. 38, 168-173
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.